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54 X-ray diffraction inspection system and method.

57 An inspection system and method for detecting the presence of selected crystalline materials, such as explosives or drugs, utilizing an x-ray source (10) and a collimated array of detectors (32) to sense radiation scattered by suitcases (14) (Fig. 1) being inspected. A signal processing system (Fig. 4) comprising a photon energy detector (40), an energy dispersive spectrum generator (42), a peak detector algorithm (44) and an e.g. explosives spectrum comparator (46) compares the measured signal with selected spectra (Fig. 3a, b or c) to determine whether specific materials are present within the inspected suitcase.

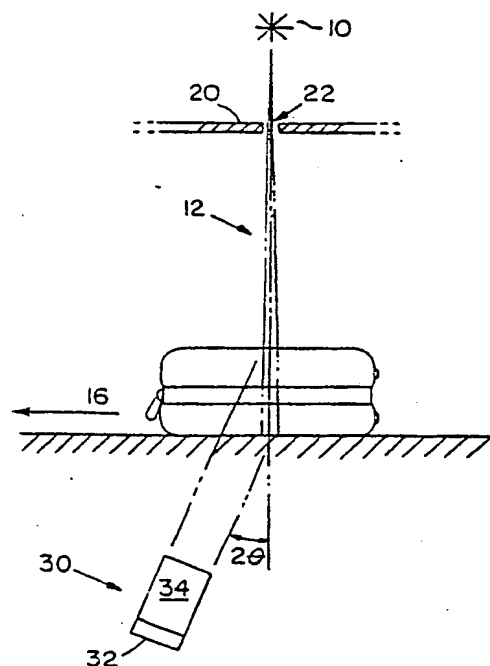


Fig. 2

EP 0 354 045 A3

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EUROPEAN SEARCH REPORT

Application Number

EP 89 30 7921

DOCUMENTS CONSIDERED TO BE RELEVANT			
Category	Citation of document with indication, where appropriate, of relevant passages	Relevant to claim	CLASSIFICATION OF THE APPLICATION (Int. Cl.5)
Y	GB-A-1 329 695 (JACK CROSSLEY NUTTER) * Column 3, lines 112-121; claims 1-10 * - - - -	1-3,5	G 01 N 23/20 G 01 V 5/00
Y	EP-A-0 271 723 (HEIMANN GmbH) * Columns 2,3 *	1-3,5	
A	- - - -	4	
P,X	EP-A-0 311 177 (PHILIPS PATENTVERWALTUNG GmbH) * Claims 1-9; figure 1 *	1-4	
A	ANALYTICAL INSTRUMENTATION, vol. 16, no. 2, 1987, pages 281-294, New York, US; M.K. SANYAL et al.: "A microprocessor based energy dispersive x-ray diffractometer" * Pages 281,282 *	1	
A	GB-A-1 081 683 (FARBENFABRIKEN BAYER AG) * Claims 1-4 *	5	
A	GB-A-1 426 102 (SOCIETE NATIONALE DES PETROLES D'AQUITAINE) * Claims 1,2 *	1,5	
A	EP-A-0 209 952 (PHILIPS PATENTVERWALTUNG GmbH) * Claims 1,2 *	1,4,5,7	
The present search report has been drawn up for all claims			
Place of search: The Hague		Date of completion of search: 26 June 91	Examiner: VAN DEN BULCKE E.
CATEGORY OF CITED DOCUMENTS X: particularly relevant if taken alone Y: particularly relevant if combined with another document of the same category A: technological background Q: non-written disclosure P: intermediate document T: theory or principle underlying the invention E: earlier patent document, but published on, or after the filing date D: document cited in the application I: document cited for other reasons &: member of the same patent family, corresponding document			

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